



IECEX Quality Assessment Report Summary

INTERNATIONAL ELECTROTECHNICAL COMMISSION IEC Certification Scheme for Explosive Atmospheres

for rules and details of the IECEx Scheme visit www.iecex.com

QAR Reference No.	NL/DEK/QAR13.0030/04	Status	Current
QAR Free Ref. No.	381622300	Date of Issue	2019-06-06
Detail of change	Reassessment audit	Valid until	2022-08-30
Site(s) audited	Crystal Engineering Corporation, 708 Fiero Lane, Suite 9 , San Luis Obispo, CA 93401, USA	Audit date	2019-04-29
Issuing ExCB	DEK - DEKRA Certification B.V.		
Manufacturer	Crystal Engineering Corporation, 708 Fiero Lane, Suite 9 , San Luis Obispo, CA 93401, USA		
Location of Manufacturer	United States of America		
Product information	Digital Test Gauges and Pressure Recorders		
Protection concept	Ex i		
Related QARs			
NL/DEK/QAR13.0030/00	NL/DEK/QAR13.0030/01	NL/DEK/QAR13.0030/02	NL/DEK/QAR13.0030/03
NL/DEK/QAR13.0030/04			
Related Certificates (manual insertion)	FTZU 06ATEX0010X, FTZU 12ATEX0048X, FTZU 18ATEX 0043X, SIRA 09ATEX2008X		
Related Certificates (automatic linking)	N/A		
Related Certificates for previous versions			
IECEX FTZU 10.0018X issue: 2	IECEX FTZU 12.0009X issue: 2	IECEX FTZU 12.0009X issue: 3	IECEX FTZU 18.0012X issue: 0
IECEX SIR 09.0053X issue: 4	IECEX SIR 09.0053X issue: 5		

Comments

The listed ATEX Certificates are related to Notification No. DEKRA 13ATEXQ0151.